

## MINISTRY OF SUPPLY (S.R.D.E.)

Specification MOS/CV1341/Is Dated 26.4.46 To be used in conjunction w	SECURITY Specification Valve Restricted Restricted								
——≯indicates a change									
TYPE OF VALVE: - Screened per CATHODE: - Indirectly Glass-unmetted MSP4	MARKING See Kl001/4								
RATING	Note	BASE B7							
Heater voltage (V) Heater current (A) Max. anode voltage (V) Max. screen voltage (V) Mutual conductance (mA/V)  CAPACITANCES (pF) (Max) Cag Cae	4.0 1.0 250 100 4.0 0.03 7.6 17.2	A	Pin 1 2 3 4 5 6 7	No c Cont Supp Heat Heat Cath	er ode en grid	d grid			
Cge <u>NOTES</u>	TOP CAP See Kl001/AI/D5.1								
A. Measured at Va = 200, Vgl = 0  This valve type is obso	<u>DIMENSIONS</u> See KlOOl/AI/Dl								
this specification is f purposes only.				Max.					
L			A m	m	130	141			

В mm

## **CVI34I**

## TESTS

To be performed in addition to those applicable in Kl001

	Test conditions						Test		Limits		No.		
									Min.	Max.	tested	Notes	
a			AIII				Capac:	itano	ces(pF)		***		
	H.		Links L.P.	1 1								,	
	TCl	-	2										
	101		2		1,3,4,5, 6,7,8,9, 10,TC2		(i)	Cag		_	0.03	T.A	
							<b>\</b>	- 0					
	TCl		3.4.5	6,	, 1,2,8,9, 10,TC2								
			7				(ii)	Cae			7.6	6	
	2		3.4.5	6.	1.8	3,9,10,						per	
			7		TĆ:	l,TC2	(iii)	Cge		-	17.2	week	
	Vh	Va	Vg2	٧g	3	Vgl							
ъ	4.0	-	-	-	•	-	Ih		(A)	0.9	1.1	100%	
			<u> </u>	_								or S	
С	4.0	200	100	C	)	-1	Ia		(mA)	3.0	8.0	100%	
đ	4.0	200	100	С	)	-1	Ig2		(mA)	1	2.75	100%	
е	4.0	200	100	C	)	-1	gm		(mA/V)	2.15	4.5	100%	
f	4.0	200	100	0	`	-2	Rev	Ig	(uA)	-	1.7	100%	
g	4.0	4000	50	C	)	Ia=							
						25uA	Vg (	(C.O.	.) (४)	-	<b>-2</b> 5	5 <b>%</b> (20)	1 & 3
h	4.0	4000	50		)	1.OmA	Flasho	over	test	l	L	<del>  `                                   </del>	
	,,,						No abr		5%	2 & 3			
							be app	parer	(20)				

## NOTES

- 1. H.T. to be applied only as long as is necessary to take reading.
- 2. During this test flashovers may be allowed to occur, providing such flashovers do not render the valve inoperative.
- 3. The use of an approved high voltage conditioning apparatus is accepted as alternative to tests f and g.